

## 2-[(Tri-2-pyridylmethyl)iminomethyl]phenol

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## Key indicators

Single-crystal X-ray study

T = 298 K

Mean  $\sigma(\text{C}-\text{C}) = 0.002 \text{ \AA}$ 

R factor = 0.036

wR factor = 0.102

Data-to-parameter ratio = 14.5

For details of how these key indicators were automatically derived from the article, see <http://journals.iucr.org/e>.

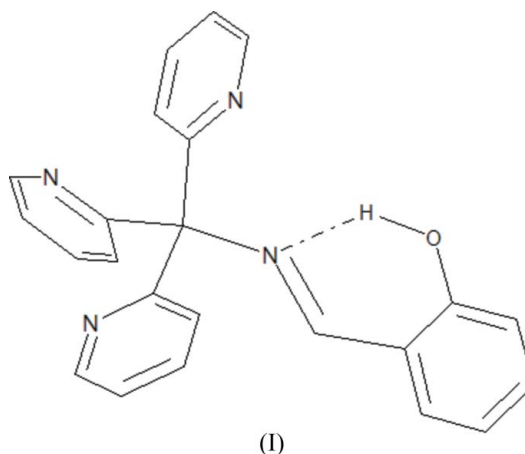
The title compound,  $\text{C}_{23}\text{H}_{18}\text{N}_4\text{O}$ , crystallizes as a discrete molecular species with an intramolecular  $\text{N}-\text{H}\cdots\text{O}$  hydrogen bond.

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## Comment

Schiff bases are of great importance in coordination chemistry and supramolecular chemistry (Martell *et al.*, 2001) and here we report the structure of the title compound, (I) (Fig. 1). The hydroxyl group forms a strong intramolecular  $\text{O}-\text{H}\cdots\text{N}$  hydrogen bond with the Schiff base N atom (Table 1).



## Experimental

The title compound was synthesized according to a method described previously (Arnold *et al.*, 1998). Yellow block-like crystals were obtained from an ethanol/water (1:1) solution. Analysis calculated for  $\text{C}_{23}\text{H}_{18}\text{N}_4\text{O}$ : C 75.39, N 15.29, H 4.95%; found (%): C 75.32, N 15.33, H 4.98%.

## Crystal data

 $\text{C}_{23}\text{H}_{18}\text{N}_4\text{O}$  $M_r = 366.41$ Triclinic,  $P\bar{1}$  $a = 8.6327 (1) \text{ \AA}$  $b = 10.6779 (2) \text{ \AA}$  $c = 10.8432 (2) \text{ \AA}$  $\alpha = 79.001 (1)^\circ$  $\beta = 85.057 (1)^\circ$  $\gamma = 72.838 (1)^\circ$  $V = 936.99 (3) \text{ \AA}^3$  $Z = 2$ Mo  $K\alpha$  radiation $\mu = 0.08 \text{ mm}^{-1}$  $T = 298 (2) \text{ K}$  $0.30 \times 0.20 \times 0.12 \text{ mm}$ 

## Data collection

Siemens SMART CCD  
diffractometerAbsorption correction: multi-scan  
(SADABS; Sheldrick, 1996) $T_{\min} = 0.976$ ,  $T_{\max} = 0.990$ 

4356 measured reflections

3689 independent reflections

3297 reflections with  $I > 2\sigma(I)$  $R_{\text{int}} = 0.018$

Refinement

$R[F^2 > 2\sigma(F^2)] = 0.036$   
 $wR(F^2) = 0.102$   
 $S = 1.06$   
 3689 reflections

254 parameters  
 H-atom parameters constrained  
 $\Delta\rho_{\max} = 0.18 \text{ e \AA}^{-3}$   
 $\Delta\rho_{\min} = -0.18 \text{ e \AA}^{-3}$

**Table 1**  
 Hydrogen-bond geometry ( $\text{\AA}$ ,  $^\circ$ ).

$D-H\cdots A$	$D-H$	$H\cdots A$	$D\cdots A$	$D-H\cdots A$
$O1-H1\cdots N4$	0.82	1.84	2.5638 (12)	147

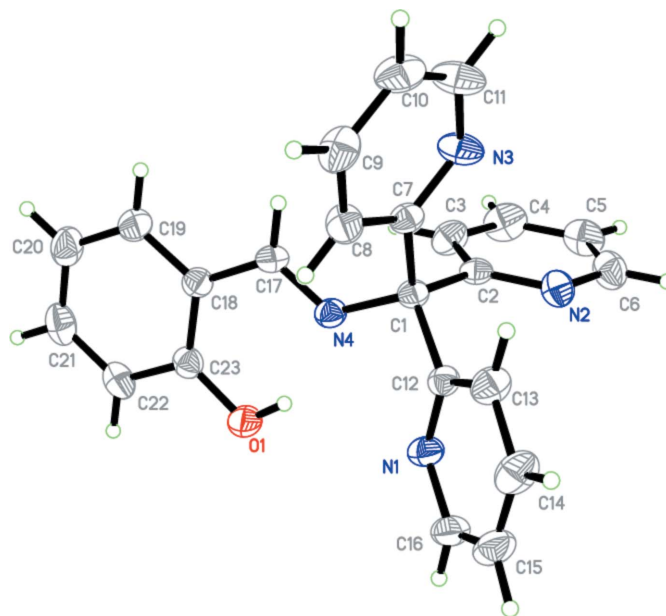
All H atoms were positioned geometrically, with  $O-H = 0.82$  and  $C-H = 0.93 \text{ \AA}$ , and refined as riding, with  $U_{\text{iso}}(\text{H}) = 1.2U_{\text{eq}}(\text{C})$  or  $U_{\text{iso}}(\text{H}) = 1.5U_{\text{eq}}(\text{O})$ .

Data collection: *SMART* (Siemens, 1996); cell refinement: *SAINT* (Siemens, 1994); data reduction: *SAINT* and *XPREP* (Siemens, 1996); program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL* (Sheldrick, 2000); software used to prepare material for publication: *SHELXTL*.

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References

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**Figure 1**  
 The molecular structure of the title compound. Displacement ellipsoids are drawn at the 30% probability level.

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